Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

10751176

GEIER ET AL.

Examiner

Art Unit

Flores, Leon

2635

SEARCHED					
Class	Subclass	Date	Examiner		
375	130,134, 137, 142, 145, 150, 316, 343, 344, 355	12/06/2006	LF		
342	357.12	12/06/2006	LF		

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted with SPE Vu Le in regards to the patentability of the claims	12/11/2006	LF		
Consulted with Primary Lin Ye in regards to claim 1.	12/06/2006	LF		
Checked for double patenting	12/07/2006	LF		
Consulted with SPE David Payne in regards to the amendments of the claims.	3/20/2007	LF		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examine		

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